

**ECE 313 - Section B**  
**Final Exam**  
**Fall 2013**

<b>Name:</b> _____  <b>NetID:</b> _____
---

- **Be sure that your exam booklet has 12 pages.**
- **Write your name at the top of each page.**
- This is a **closed book** exam.
- You may consult your three 8.5" x 11" sheets of notes.
- No calculators, cell phones, PDAs, tablets, or laptop computers are allowed.
- **Please show all your work.** Answers without appropriate justification will receive **very little** or **no credit**.
- If you need extra space, use the back of the previous page.

**Problem 1** \_\_\_\_\_ (40 pts)

**Problem 2** \_\_\_\_\_ (15 pts)

**Problem 3** \_\_\_\_\_ (20 pts)

**Problem 4** \_\_\_\_\_ (15 pts)

**Problem 5** \_\_\_\_\_ (10 pts)

**Problem 6** \_\_\_\_\_ (10 pts)

**TOTAL** \_\_\_\_\_ (110 pts)

**Problem 1** (40 pts) – For each of the following parts, provide a short answer in the space provided, or choose the statement that is TRUE. Show your work and a justification for your answer to get partial credit.

**Part A** (3 pts): A component has a constant hazard/failure rate. Which distribution best models the time to failure of the component? Write the failure density function  $f(t)$  and reliability function  $R(t)$  for it.

**Part B** (4 pts) We have three components in series, each with a constant failure rate of  $\lambda$ , write the reliability function  $R(t)$ , the hazard rate  $h(t)$ , and the failure density function  $f(t)$  of the system.

**Part C** (4 pts): The CPU time requirement of a typical program measured in minutes is found to follow a three stage Erlang distribution with  $\lambda = \frac{1}{2}$ . What is the probability that the CPU demand of a program will exceed 1 min?

**Problem 1, continued:**

**Part D** (4 pts): Consider a binary hypothesis testing problem where the prior probability of hypothesis  $H_0$  is  $\pi_0$  and the prior probability of hypothesis  $H_1$  is  $\pi_1$ . Denote the probabilities of false alarm and missed detection for the ML decision rule by  $P_{FA}^{ML}$  and  $P_{MD}^{ML}$ , respectively. Similarly, denote the probabilities of false alarm and missed detection for the MAP decision rule by  $P_{FA}^{MAP}$  and  $P_{MD}^{MAP}$ , respectively. State whether the following statements are TRUE or FALSE. Include a short explanation:

(a)  $P_{FA}^{ML} \cdot \pi_0 + P_{MD}^{ML} \cdot \pi_1 \geq P_{FA}^{MAP} \cdot \pi_0 + P_{MD}^{MAP} \cdot \pi_1$ .

(b) If  $\pi_0 = 0.5$  then  $P_{MD}^{ML} = P_{MD}^{MAP}$ .

**Part E** (5 pts): Let  $X$  and  $Y$  be two continuous random variables with joint density function:

$$f(x, y) = \begin{cases} 4e^{-2(x+y)}, & 0 \leq x < \infty, 0 \leq y < \infty \\ 0, & \text{otherwise} \end{cases}$$

(a) Are  $X$  and  $Y$  independent? Why?

(b) Are  $X$  and  $Y$  positively correlated, uncorrelated, or negatively correlated?

**Problem 1, continued:**

**Part F** (10 pts): Suppose  $n$  fair dice are independently rolled. Let:

$$X_k = \begin{cases} 1 & , \text{if } 1 \text{ or } 2 \text{ show on the } k^{\text{th}} \text{ die} \\ 0 & , \text{else} \end{cases}$$
$$Y_k = \begin{cases} 1 & , \text{if } 3 \text{ shows on the } k^{\text{th}} \text{ die} \\ 0 & , \text{else} \end{cases}$$

Let  $X = \sum_{k=1}^n X_k$  and  $Y = \sum_{k=1}^n Y_k$ . State whether the following statements are TRUE or FALSE. Show your work to get credit for your answer.

(a)  $\text{Var}(X_k) = \frac{2}{9}$

(b)  $\text{Var}(X) = \frac{2n}{9}$

(c)  $\text{Cov}(X_1, Y_2) = -2$

(d)  $\text{Cov}(X_1, Y_1) \neq \text{Cov}(X_2, Y_2)$

(e)  $\rho_{X,Y} = \frac{18\text{Cov}(X,Y)}{\sqrt{10n}}$

**Problem 1, continued:**

**Part G** (10 pts): Suppose the number of job requests arriving at the Blue Waters supercomputing center is Poisson distributed with an average rate of  $\lambda$  requests per minute. Each job request arriving at the center is a GPU task with the probability of  $p$ , and demands more than 10 cores with the probability of  $q$  (These two events are independent from each other). We define the following random variables:

- $X$ : the inter-arrival time of two consecutive jobs arriving at the center.
- $Y$ : the random variable indicating whether a randomly picked job is a GPU task ( $Y = 1$ ) or not ( $Y = 0$ ).
- $Z$ : the random variable indicating whether a randomly picked job needs more than 10 cores ( $Z = 1$ ) or not ( $Z = 0$ ).

Assume that  $X$ ,  $Y$ , and  $Z$  are independent. Answer the following questions:

(a) What is the distribution of  $X$ ,  $Y$ , and  $Z$ ? Write their probability density function (pdf) or probability mass function (pmf) based on the parameters  $\lambda$ ,  $p$ , and  $q$ .

$X$ : \_\_\_\_\_

$Y$ : \_\_\_\_\_

$Z$ : \_\_\_\_\_

(b) Suppose that  $E[Y^2] = \frac{1}{3}$  and that  $Var(3Y + 2Z) = 3$ . Find  $p$  and  $q$ .

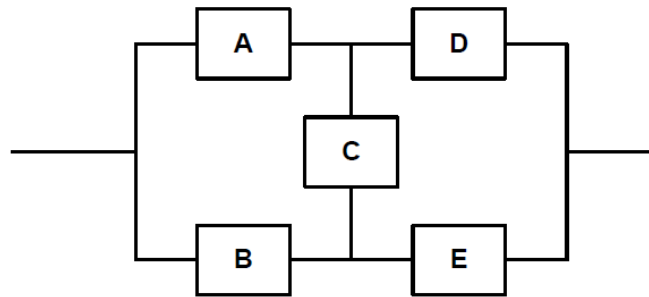
$p =$  \_\_\_\_\_

$q =$  \_\_\_\_\_

(c) Suppose that  $E\left[5X + 2Y + Z + \frac{1}{3}\right] = 2$ . Find  $\lambda$ .

$\lambda =$  \_\_\_\_\_

**Problem 2** (15 pts) – Consider the non-series-parallel system of five independent components shown in the following figure:



Use the conditional probabilities to determine an expression for the system reliability as a function of component reliabilities. Assume that the reliability of each component is equal to  $R$ . **Hint:** Try to find a node around which you can simplify the analysis.

**Problem 3** (20 pts): Suppose a certain firm has two plants A and B that produce chipsets and package them into boxes of 4. Assume that:

- 40% of the total boxes come from plant A, and 60% from plant B.
- The probability of a chipset produced by plant A being defective is 0.75, independent of all other events, and the probability of a chipset produced by plant B being defective is 0.5, independent of all other events.

A quality control crew randomly picks a box and tests each of the 4 chipsets independently for defects. Let  $X$  be the number of defective chipsets in the selected box.  $\Lambda_{ML}(X)$  is the ML decision rule to guess, based on the observation of  $X$ , whether the selected box came from plant A ( $H_0$ ) or plant B ( $H_1$ ).

**Part A** (2 pts): What are the prior probabilities of  $\pi_0$  and  $\pi_1$ ?

$\pi_0$  \_\_\_\_\_

$\pi_1$  \_\_\_\_\_

**Part B** (5 pts): What distribution best models the random variable  $X$  under each of the hypotheses  $H_0$  and  $H_1$ ? Write the probability mass function (pmf) of  $X$  under each of  $H_0$  and  $H_1$ :

Distribution under  $H_0$  :  $P(X = k|H_0) =$  \_\_\_\_\_

Distribution under  $H_1$  :  $P(X = k|H_1) =$  \_\_\_\_\_

**Part C** (7 pts): Use the table provided below or the likelihood ratio test (LRT) to describe the  $\Lambda_{ML}(X)$  decision rule and find the threshold for  $X$ .

ML	X = 0	X = 1	X = 2	X = 3	X = 4
$H_0$					
$H_1$					

$\Lambda_{ML}(X) =$

$$\Lambda_{ML}(X) = \begin{cases} X \geq \text{_____} & H_0 \\ X < \text{_____} & H_1 \end{cases}$$

**Part D** (6 pts): Calculate the probabilities of false alarm, miss detection, and error.

$P_{FA}^{ML} =$  \_\_\_\_\_

$P_{MD}^{ML} =$  \_\_\_\_\_  $P_{ERROR}^{ML} =$  \_\_\_\_\_





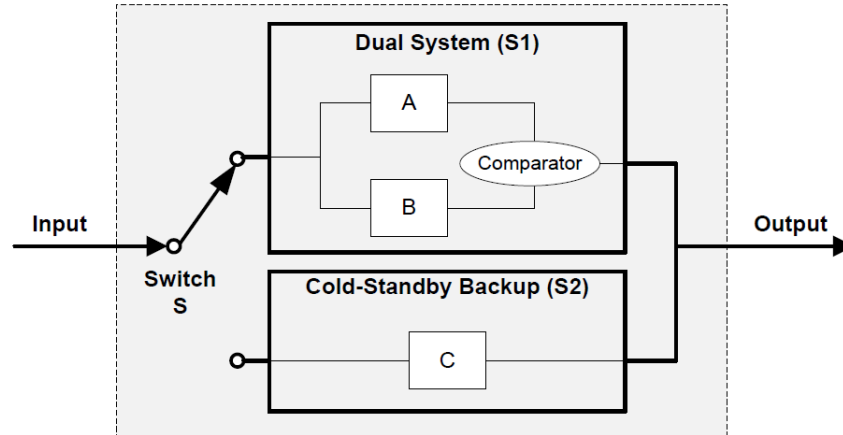
**Problem 5** (10 pts) - The amount of time a typical ECE 313 student spends on the final project has a population mean  $\mu = 3.10$  hours and standard deviation  $\sigma = 0.40$  hours. If a random sample of 16 students is selected, use the central limit theorem to answer the following questions:

**Part A** (4 pts): Let  $\bar{X}$  be the average time spent by the selected students. What is the mean and standard deviation of  $\bar{X}$ .

**Part B** (2 pts): What is the probability that the average time the selected students spend on the project will be at least 3 hours?

**Part C** (4 pts): There is an 85% chance that the average time the selected students spend on the project will be below N hours. What is N?

**Problem 6** (10 pts) – Consider the following system composed of two subsystems S1 and S2. S1 is a dual system composed of two components A and B, where the failure of any of them will cause the failure of the subsystem S1. S2 is composed of a component C which acts as a backup (cold standby) of the subsystem S1 and will be powered on only after dual subsystem fails.



Assume that A and B are identical components and the switching circuit S and the comparator are perfect. We model the lifetime of the components A, B, and C with three independent random variables  $X_1$ ,  $X_2$ , and  $X_3$ . Assume  $X_1$  and  $X_2$  are exponentially distributed with parameter  $\lambda$  and  $X_3$  is exponentially distributed with parameter  $3\lambda$ .

**Part A** (4 pts) – Find the reliability function and failure rate ( $\lambda_1$ ) of the dual subsystem (S1).

**Part B** (6 pts) – What distribution best models the time to failure of the whole system? Use the results of part A to derive the reliability function of the system in terms of  $\lambda$ .

**2-stage Hypoexponential Distribution:**

$$f(t) = \frac{\lambda_1 \lambda_2}{\lambda_2 - \lambda_1} (e^{-\lambda_1 t} - e^{-\lambda_2 t}), \quad t > 0$$

$$F(t) = 1 - \frac{\lambda_2}{\lambda_2 - \lambda_1} e^{-\lambda_1 t} + \frac{\lambda_1}{\lambda_2 - \lambda_1} e^{-\lambda_2 t}, \quad t \geq 0$$

$$h(t) = \frac{\lambda_1 \lambda_2 (e^{-\lambda_1 t} - e^{-\lambda_2 t})}{\lambda_2 e^{-\lambda_1 t} - \lambda_1 e^{-\lambda_2 t}}, \quad t > 0$$

**r-stage Erlang Distribution:**

$$f(t) = \frac{\lambda^r t^{r-1} e^{-\lambda t}}{(r-1)!}, \quad t > 0, \lambda > 0, r = 1, 2, \dots$$

$$F(t) = 1 - \sum_{k=0}^{r-1} \frac{(\lambda t)^k}{k!} e^{-\lambda t}, \quad t \geq 0, \lambda > 0, r = 1, 2, \dots$$

$$h(t) = \frac{\lambda^r t^{r-1}}{(r-1)! \sum_{k=0}^{r-1} \frac{(\lambda t)^k}{k!}}, \quad t > 0, \lambda > 0, r = 1, 2, \dots$$

